

TITLE: Liquid crystal display for testing defects of wiring in a panel

BACKGROUND OF THE INVENTION

1. Field of the Invention

5 The present invention relates generally to a liquid crystal display and, more particularly, to a liquid crystal display capable of testing defects of wiring in a panel.

2. Description of the Prior Art

FIGS. 1A to 1C are drawings showing a ~~Module-module~~ structure of having a conventional liquid crystal display.

10 As shown in the drawings, FIG. 1A comprises a X-printed circuit board (X-PCB) 2 for supplying graphic signals to a panel 1, a Y-printed circuit board (Y-PCB) 4 for applying thin film transistor (TFT) driving signals and a flexible printed circuit (FPC) 7 for connecting the PCBs.

15 ~~And,~~ FIG. 1B shows a structure ~~that~~ in which the FPC 7 is removed and FIG. 1C shows one in which that the Y-PCB 4 is removed and signals for driving a gate driver integrated circuit (IC) are applied through wiring in the panel 1.

~~Here~~ As shown, panels of each module have different shapes and wiring for
20 driving the gate driver IC is formed on the upper part of an array substrate of the panel.

FIG. 2 ~~is a drawing showing~~ illustrates a conventional ~~method of~~ configuration for a panel test. Referring to FIG. 2, odd lines of data lines (D1, D2 . . . D(2n+1)) are

connected to data odd pad ~~17b~~ 17a and even lines of the data lines (D1, D2 . . . D(2n)) are connected to data even pad ~~17a~~ 17b. In the same method, gate lines (G1, G2 . . . Gn) are connected to gate odd pad 15a and gate even pad 15b. ~~And,~~ Vcom pad 13 is connected to all pixels of the TFT array 11 on the panel and wiring 20 is formed ~~on adjacent~~ the corner of the upper part of panel 10.

Then, signals are applied to the five resulting pads in order to test whether a unit pixel is normally operated or not. That is, it is possible to test a short anomaly of a line and pixel by applying voltage to the gate odd pad 15a, the gate even pad 15b, the data odd pad 17a, the data even pad 17b and the Vcom pad 13.

However, the conventional liquid crystal display has a disadvantage in that it is difficult to test for anomalies, such as disconnection and short, by wiring formed on the upper part of panel, and further requires additional devices ~~is required~~ to test defects of the wiring.

SUMMARY OF THE INVENTION

Therefore, the present invention ~~has been made~~ is intended to solve the above problems and an object of the present invention is to provide a liquid crystal display for testing defects that may be present of wiring in panel wiring capable of testing disconnection and short anomalies of wiring in the panel wiring when signals are applied, by connecting data line or gate line or common voltage line in a panel to each pad

through wiring formed ~~on the outside of panel~~ in a zigzag shape on the outside of the panel.

In order to accomplish the above object, the present invention comprises: a TFT
5 array unit ~~comprising~~ including a plurality of gate lines and data lines formed in a matrix shape, having TFT transistors at the intersection of ~~the each pair of~~ gate lines and ~~the~~ data lines; a data pad unit commonly connected to the plurality of data lines; for receiving signals for driving the data line; and a wiring unit for testing defects of the data line being connected between the data pad unit and the data line; for testing disconnection and short
10 anomalies of the data line.

The data pad unit comprises a first data pad ~~unit~~ commonly connected to the odd data ~~line~~ lines of the plurality of data lines; for receiving signals for driving the odd data lines ~~line~~ and a second data pad ~~unit~~ commonly connected to the even data lines ~~line~~ of
15 the plurality of data lines; for receiving signals for driving the even data lines ~~line~~.

The wiring unit for testing defects of the data line further comprises a first wiring unit for testing defects of the data line, which is connected between the first data pad ~~unit~~ and the odd data line, normally used for testing disconnection and short anomalies of the
20 odd data line, and a second wiring unit for testing defects of the data line, which is connected between the second data pad ~~unit~~ and the even data line, and is used for testing disconnection and short anomalies of the even data line.

The first and the second wiring units for testing defects of the data line preferably are formed in a zigzag shape.

According to another embodiment of the present invention, a liquid crystal
5 display for testing defects of wiring in a panel comprises: a TFT array unit ~~comprising~~
including a plurality of gate lines and data lines formed in a matrix shape, having TFT
transistors at the intersection of ~~the~~ each of the gate lines and the data lines; a gate pad
unit commonly connected to the plurality of gate lines, for receiving signals for driving
the gate line; and a wiring unit for testing defects of the gate line being connected
10 between the gate pad unit and the gate line, used for testing disconnection and short
anomalies of the gate line.

The gate pad unit further comprises a first gate pad unit commonly connected to
the odd gate line of the plurality of gate lines, for receiving signals for driving the odd
15 gate line and a second gate pad unit commonly connected to the even gate line of the
plurality of gate lines, for receiving signals for driving the even gate line.

The wiring unit for testing defects of the gate line comprises a first wiring unit for
testing defects of the ~~first~~ gate line connected between the first gate pad unit and the odd
20 gate line, for testing disconnection and short anomalies of the odd gate line and a second
wiring unit for testing defects of the ~~second~~ gate line connected between the second gate
pad and the even gate line, for testing disconnection and short anomalies of the even gate
line.

The first and the second wiring units for testing defects of the gate lines preferably are formed in a zigzag shape.

5 According to still another embodiment of the present invention, a liquid crystal display comprises: a TFT array unit ~~comprising~~ including a plurality of gate lines and data lines formed in a matrix shape, having a TFT transistors on each pixel at the intersection of the gate line and the data line; a common voltage pad unit for applying a common voltage to the common voltage line connected to each pixel; and a wiring unit
10 for testing defects of the common voltage line connected between the common voltage line and the common voltage pad unit, for testing disconnection and short anomalies of the common voltage line.

 The common voltage pad unit comprises a first common voltage pad ~~unit~~
15 commonly connected to the odd common voltage line of the plurality of common voltage lines, for receiving signals for driving the odd common voltage line and a second common voltage pad ~~unit~~ commonly connected to the even common voltage line of the plurality of common voltage lines, for receiving signals for driving the even common voltage line.

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 The wiring unit for testing defects of the common voltage line comprises a first wiring unit for testing defects of the common voltage line, connected between the first common voltage pad ~~unit~~ and the odd common voltage line, for testing disconnection

and short anomalies of the odd common voltage line and a second wiring unit for testing defects of the common voltage line, connected between the second common voltage pad ~~unit~~ and the even common voltage line, for testing disconnection and short anomalies of the even common voltage line.

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The first and the second wiring units for testing defects of the common voltage line preferably are formed in a zigzag shape.

According to the present invention, it is possible to test defects ~~of in the~~ wiring ~~in~~ of a panel by a conventional panel test method, thereby improving reliability of the panel.

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~~BRIEF~~ BRIEF DESCRIPTION OF THE DRAWINGS

FIGS. 1A to 1C are drawings showing module structure of a general conventional liquid crystal display-;

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FIG. 2 is a drawing showing a conventional panel test method-;

FIGS. 3A and 3B are block diagrams showing a liquid crystal display for testing defects of wiring in a panel according to the present invention-; and

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FIGS. 4A and 4B ~~are drawings showing~~ illustrate a method of testing disconnection and short anomalies of a wiring in a panel according to the present invention.

DETAILED DESCRIPTION OF THE ~~INVENTION~~ PREFERRED EMBODIMENTS

The above objects, and other features and advantages of the present invention will
5 become more apparent after reading the following detailed description when taken in
conjunction with the appended drawings.

FIGS. 3A and 3B are drawings showing a method of testing wiring in a panel
according to the present invention.

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Referring to FIG. 3A, a TFT array unit 11 in a panel 10 is arranged with a
plurality of gate lines G1, ~~G₂~~, G2 . . . Gn and data lines D1, D2. . . Dn from the TFT array
unit. The odd lines of the gate lines G1, G2 . . . Gn are connected to a gate odd pad 15a
and the even lines are connected to a gate even pad 15b. ~~The~~ In the same manner, the data
15 lines D1, D2 . . . Dn are connected to a data odd pad 17a and a data even pad 17b. The
zigzag connection wiring 30a on the upper part of panel 10 is connected to a first line D1
of the data ~~odd-even~~ pad 17a-17b in series.

Referring to FIG. 3B, a test structure is formed in the same method as that in FIG.
20 3A. However, wiring is formed in a separated zigzag connection wiring pattern 30b and
then, is connected to a first line D1 of data odd pad 17a and a first line D2 of data even
pad 17b in series. Therefore, it is possible to test for disconnection and short anomalies of
wiring by applying a signal for the test to data odd pad 17a and to data even pad 17b.

When a short is generated, the TFT of the data even line, ~~where to which~~ a signal is not applied, is also operated, as well as in the data odd line, to which a signal is applied.

FIGS. 4A and 4B ~~are drawings showing~~ illustrate a method of testing
5 disconnection and short anomalies of wiring in a panel according to the present invention.

Referring to FIG. 4A, when disconnection is generated between wiring of a panel, the disconnected wiring is connected to a first line D1 of data odd pad 17a. Therefore, when a signal is applied to the data odd pad 17a, the TFT of the disconnected first line D1 is not
10 operated and the TFTs of other data odd lines D3, D5, etc. . . . are normally operated.

FIG. 4B shows a method of testing defects when a short is generated between wiring in a panel. Referring to FIG. 4B, the data odd pad 17a is connected to wiring connected to data even pad 17b. Therefore, when a signal is applied to the data odd pad 17a, the TFT of the ~~second~~ first data line ~~D2~~ D1 is operated, as well as the TFT of the
15 ~~first~~ second data line ~~D1~~ D2, to which a signal is not applied. If the two are operated at the same time when a signal is applied to only one, it is determined that short defects are generated present.

Although it is not shown in the drawings, it is possible to also test defects by connecting the same method to gate odd pad 15a and gate even pad 15b and by
20 connecting the zigzag wiring 30a to the common voltage Vcom pad 13 in series.

As described above, according to the present invention, it is possible to test defects of wiring in a panel by connecting wiring in a zigzag shape or by separating and

connecting wiring in a zigzag shape and then, connecting the resultant to the gate pad unit, the data pad unit and the common voltage pad unit.

5 ~~And, according~~ According to the present invention, it is possible to ~~remove~~ omit a stand alone Flexible Printed Circuit FPC or a Printed Circuit Board PCB, thereby reducing manufacturing cost and the size of the resulting product.

10 Although ~~the~~ preferred embodiments of this invention ~~has~~ have been disclosed for illustrative purposes, those skilled in the art will appreciate that various modifications, alterations, additions and substitutions are possible, without departing from the scope and spirit of the invention as set forth in the following claims.